Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	•
10/007,259	JANG ET AL.	
Examiner	Art Unit	
Brian E. Miller	2652	

SEARCHED				
Class	Subclass	Date ·	Examiner	
360	234.5			
360	265.7			
360	265.9			
360	266			
360	266.3			
360	97.01	(.		
360	245.8			
360	245.9	4/26/2005	BEM	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
360	264.2	١.	\	
360	234.5	4/26/2005	ВЕМ	
360	245.9		u	

	DATE	EXMR
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